

Search Notes

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10/571,195

Examiner

Patricia Leith

Applicant(s)/Patent under
Reexamination

LEE ET AL.

Art Unit

1655

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST:JPO,EPO,DERWENT,USPATF ULL,USGPUBS,OCBACKFILE	11/20/2007	PL
Inventor name search PALM/EAST	11/20/2007	PL
STN: Indexed BIOSCIENCE cluster & Napralert database (approx. 68 databases)	11/20/2007	PL